1. General description

Complementary N/P-channel enhancement mode Field-Effect Transistor (FET) in a leadless ultra small DFN1010B-6 (SOT1216) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

2. Features and benefits

- Trench MOSFET technology
- Very low threshold voltage for portable applications: V_{GS(th)} = 0.7 V
- Leadless ultra small and ultra thin SMD plastic package: 1.1 × 1.0 × 0.37 mm
- ElectroStatic Discharge (ESD) protection > 1 kV HBM

3. Applications

- · Relay driver
- High-speed line driver
- · Level shifter
- Power management in battery-driven portables

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit	
TR1 (N-channe	TR1 (N-channel), Static characteristics							
R _{DSon}	drain-source on-state resistance	V_{GS} = 4.5 V; I_D = 600 mA; T_j = 25 °C		-	470	620	mΩ	
TR2 (P-channe	el), Static characteristic	s						
R _{DSon}	drain-source on-state resistance	V_{GS} = -4.5 V; I_D = -500 mA; T_j = 25 °C		-	1.02	1.4	Ω	
TR1 (N-channe	el)							
V _{DS}	drain-source voltage	T _j = 25 °C		-	-	20	V	
I _D	drain current	V _{GS} = 4.5 V; T _{amb} = 25 °C	[1]	-	-	600	mA	
TR2 (P-channe	TR2 (P-channel)							
V _{DS}	drain-source voltage	T _j = 25 °C		-	-	-20	V	
I _D	drain current	V_{GS} = -4.5 V; T_{amb} = 25 °C	[1]	-	-	-500	mA	





[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source TR1		D1 D2
2	G1	gate TR1	7 6	
3	D2	drain TR2	2 5	G1 $G2$ $G2$
4	S2	source TR2	8 6	
5	G2	gate TR2	3 4	
6	D1	drain TR1	Transparent top view	S1 S2 017aaa262
7	D1	drain TR1	DFN1010B-6 (SOT1216)	
8	D2	drain TR2		

6. Ordering information

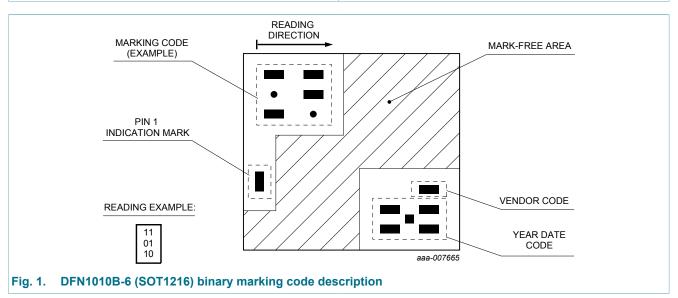
Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
PMCXB900UE	DFN1010B-6	DFN1010B-6: plastic thermal enhanced ultra thin small outline package; no leads; 6 terminals	SOT1216			

7. Marking

Table 4. Marking codes

Type number	Marking code
PMCXB900UE	10 00 00



8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
TR1 (N-cha	annel)				·	
V _{DS}	drain-source voltage	T _j = 25 °C		-	20	V
V_{GS}	gate-source voltage			-8	8	V
I _D	drain current	V_{GS} = 4.5 V; T_{amb} = 25 °C	[1]	-	600	mA
	V _{GS} = 4.5 V; T _{amb} = 100 °C	[1]	-	400	mA	
I _{DM}	peak drain current	T_{amb} = 25 °C; single pulse; $t_p \le 10 \mu s$		-	2.5	Α
P _{tot}	total power dissipation	T _{amb} = 25 °C	[2]	-	265	mW
				-	380	mW
		T _{sp} = 25 °C		-	4025	mW
TR1 (N-cha	annel), Source-drain diode					
Is	source current	T _{amb} = 25 °C	[1]	-	400	mA
TR2 (P-cha	annel)				'	
V_{DS}	drain-source voltage	T _j = 25 °C		-	-20	V
V _{GS}	gate-source voltage			-8	8	V

PMCXB900UE All information provided in this document is subject to legal disclaimers. © NXP N.V. 2013. All rights reserved

Symbol	Parameter	Conditions		Min	Max	Unit
I _D	drain current	V _{GS} = -4.5 V; T _{amb} = 25 °C	[1]	-	-500	mA
		V_{GS} = -4.5 V; T_{amb} = 100 °C	[1]	-	-300	mA
I _{DM}	peak drain current	T_{amb} = 25 °C; single pulse; $t_p \le 10 \mu s$		-	-2	Α
P _{tot} total power dissip	total power dissipation	T _{amb} = 25 °C	[2]	-	265	mW
			[1]	-	380	mW
		T _{sp} = 25 °C		-	4025	mW
TR2 (P-chani	nel), Source-drain diode	'	'	_		
I _S	source current	T _{amb} = 25 °C	[1]	-	-350	mA
Per device						
Tj	junction temperature			-55	150	°C
T _{amb}	ambient temperature			-55	150	°C
T _{stg}	storage temperature			-65	150	°C

- Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm². Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

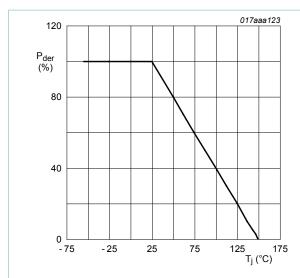


Fig. 2. MOSFET transistor: Normalized total power dissipation as a function of junction temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

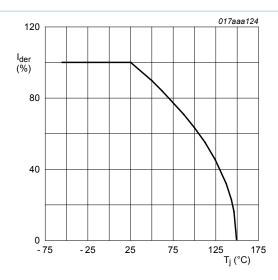


Fig. 3. **MOSFET transistor: Normalized continuous** drain current as a function of junction temperature

$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

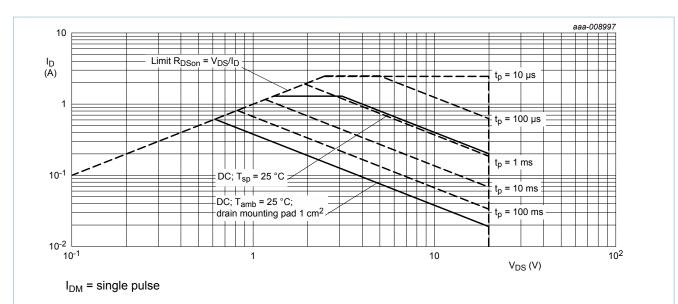


Fig. 4. TR1 (N-channel): safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

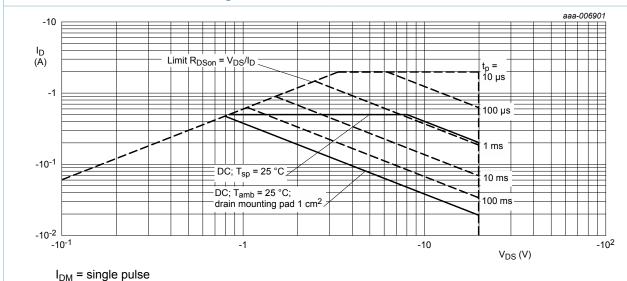


Fig. 5. TR2 (P-channel): safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
TR1 (N-cha	nnel)						
R _{th(j-a)}	thermal resistance	in free air	[1]	-	410	475	K/W
from junction to ambient		[2]	-	285	330	K/W	
$R_{th(j-sp)}$	thermal resistance from junction to solder point			-	27	31	K/W
TR2 (P-cha	nnel)			1			
R _{th(j-a)}	thermal resistance	in free air	[1]	-	410	475	K/W
fro	from junction to ambient		[2]	-	285	330	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point			-	27	31	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper; tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm².

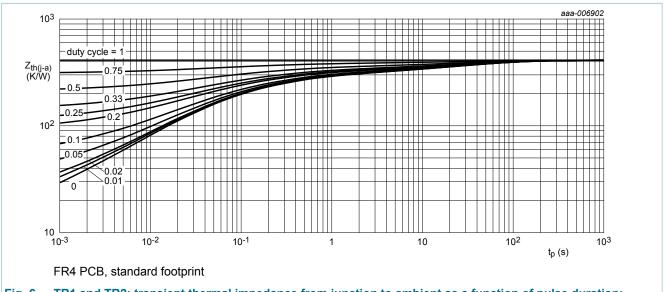
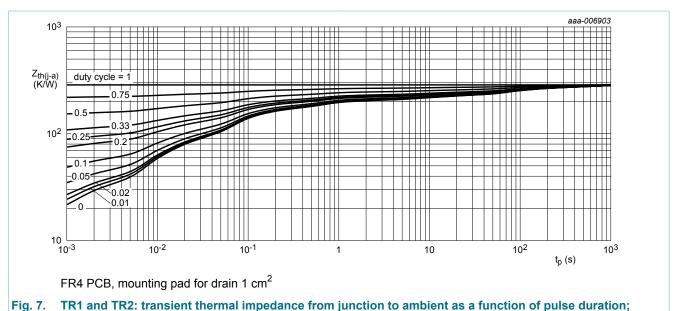


Fig. 6. TR1 and TR2: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

20 V, complementary N/P-channel Trench MOSFET



typical values

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
TR1 (N-cha	nnel), Static characteristic	es				
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	20	-	-	V
V_{GSth}	gate-source threshold voltage	$I_D = 250 \ \mu A; \ V_{DS} = V_{GS}; \ T_j = 25 \ ^{\circ}C$	0.49	5 0.7	0.95	V
I _{DSS}	drain leakage current	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μA
I _{GSS} gate leakage current	V _{GS} = 8 V; V _{DS} = 0 V; T _j = 25 °C	-	-	10	μA	
		V_{GS} = -8 V; V_{DS} = 0 V; T_j = 25 °C	-	-	-10	μA
		$V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	1	μA
		V_{GS} = -4.5 V; V_{DS} = 0 V; T_j = 25 °C	-	-	-1	μA
R _{DSon}	drain-source on-state	V_{GS} = 4.5 V; I_{D} = 600 mA; T_{j} = 25 °C	-	470	620	mΩ
	resistance	V_{GS} = 4.5 V; I_{D} = 600 mA; T_{j} = 150 °C	-	760	1000	mΩ
		V_{GS} = 2.5 V; I_{D} = 500 mA; T_{j} = 25 °C	-	620	850	mΩ
		V_{GS} = 1.8 V; I_{D} = 100 mA; T_{j} = 25 °C	-	845	1300	mΩ
		V_{GS} = 1.5 V; I_{D} = 10 mA; T_{j} = 25 °C	-	1125	3000	mΩ
		V_{GS} = 1.2 V; I_D = 1 mA; T_j = 25 °C	-	2210	-	mΩ
9 _{fs}	transfer conductance	V _{DS} = 5 V; I _D = 600 mA; T _j = 25 °C	-	1	-	S

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
TR1 (N-cha	nnel), Dynamic characteri	stics	'			
Q _{G(tot)}	total gate charge	V _{DS} = 10 V; I _D = 600 mA; V _{GS} = 4.5 V;	-	0.4	0.7	nC
Q _{GS}	gate-source charge	T _j = 25 °C	-	0.1	-	nC
Q_{GD}	gate-drain charge		-	0.1	-	nC
C _{iss}	input capacitance	V _{DS} = 10 V; f = 1 MHz; V _{GS} = 0 V;	-	21.3	-	pF
C _{oss}	output capacitance	T _j = 25 °C	-	5.4	-	pF
C _{rss}	reverse transfer capacitance		-	4.2	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 10 V; I_{D} = 600 mA; V_{GS} = 4.5 V;	-	5.6	-	ns
t _r	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	9.2	-	ns
t _{d(off)}	turn-off delay time		-	19	-	ns
t _f	fall time		-	51	-	ns
TR1 (N-cha	nnel), Source-drain diode	characteristics	ı	1	1	
V_{SD}	source-drain voltage	$I_S = 360 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	8.0	1.2	V
TR2 (P-cha	nnel), Static characteristic	es	'			,
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = -250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C}$	-20	-	-	V
V_{GSth}	gate-source threshold voltage	$I_D = -250 \ \mu A; \ V_{DS} = V_{GS}; \ T_j = 25 \ ^{\circ}C$	-0.45	-0.7	-0.95	V
I _{DSS}	drain leakage current	V _{DS} = -20 V; V _{GS} = 0 V; T _j = 25 °C	-	-	-1	μA
I _{GSS}	gate leakage current	V _{GS} = 8 V; V _{DS} = 0 V; T _j = 25 °C	-	-	10	μA
		V _{GS} = -8 V; V _{DS} = 0 V; T _j = 25 °C	-	-	-10	μA
		V _{GS} = 4.5 V; V _{DS} = 0 V; T _j = 25 °C	-	-	1	μA
		V _{GS} = -4.5 V; V _{DS} = 0 V; T _j = 25 °C	-	-	-1	μA
R _{DSon}	drain-source on-state	V_{GS} = -4.5 V; I_D = -500 mA; T_j = 25 °C	-	1.02	1.4	Ω
	resistance	V _{GS} = -4.5 V; I _D = -500 mA; T _j = 150 °C	-	1.54	2.1	Ω
		V_{GS} = -2.5 V; I_D = -200 mA; T_j = 25 °C	-	1.27	2.2	Ω
		V_{GS} = -1.8 V; I_D = -40 mA; T_j = 25 °C	-	1.7	3.3	Ω
		V_{GS} = -1.5 V; I_D = -10 mA; T_j = 25 °C	-	2.3	5	Ω
		V_{GS} = -1.2 V; I_D = -1 mA; T_j = 25 °C	-	3.5	-	Ω
9 _{fs}	transfer conductance	V_{DS} = -10 V; I_{D} = -500 mA; T_{j} = 25 °C	-	480	-	mS
TR2 (P-cha	nnel), Dynamic characteri	stics	<u> </u>	1	1	1
Q _{G(tot)}	total gate charge	V_{DS} = -10 V; I_{D} = -450 mA;	-	1.19	2.1	nC
Q _{GS}	gate-source charge	$V_{GS} = -4.5 \text{ V}; T_j = 25 \text{ °C}$	-	0.17	-	nC
Q_{GD}	gate-drain charge	-	_	0.1	_	nC

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
C _{iss}	input capacitance	V_{DS} = -10 V; f = 1 MHz; V_{GS} = 0 V;		-	43	-	pF
C _{oss}	output capacitance	T _j = 25 °C		-	14	-	pF
C _{rss}	reverse transfer capacitance			-	8	-	pF
t _{d(on)}	turn-on delay time	V _{DS} = -10 V; I _D = -450 mA;		-	2.3	-	ns
t _r	rise time	$V_{GS} = -4.5 \text{ V}; R_{G(ext)} = 6 \Omega; T_j = 25 \text{ °C}$		-	5	-	ns
$t_{d(off)}$	turn-off delay time			-	13.5	-	ns
t _f	fall time			-	6	-	ns
TR2 (P-cha	annel), Source-drain diode	characteristics	1		'		,
V_{SD}	source-drain voltage	I_S = -115 mA; V_{GS} = 0 V; T_j = 25 °C		-	-0.7	-1.2	V

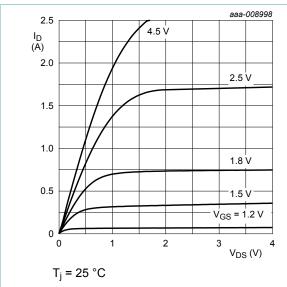


Fig. 8. TR1: output characteristics; drain current as a function of drain-source voltage; typical values

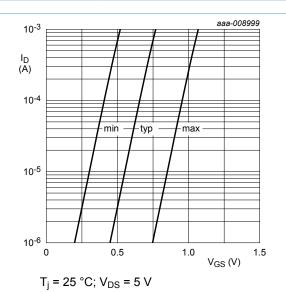


Fig. 9. TR1: sub-threshold drain current as a function of gate-source voltage

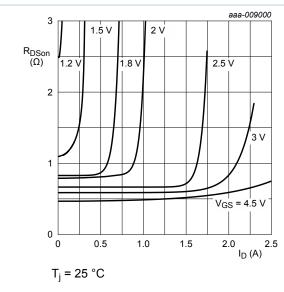


Fig. 10. TR1: drain-source on-state resistance as a function of drain current; typical values

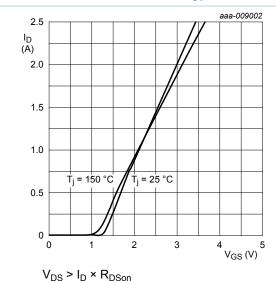


Fig. 12. TR1: transfer characteristics; drain current as a function of gate-source voltage; typical values

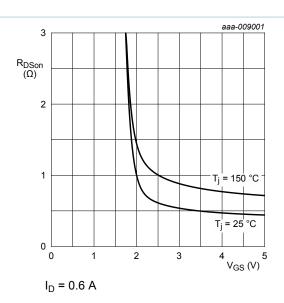


Fig. 11. TR1: drain-source on-state resistance as a function of gate-source voltage; typical values

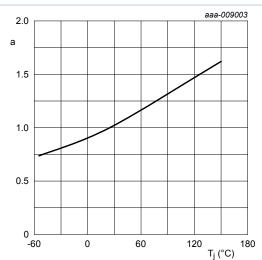


Fig. 13. TR1: normalized drain-source on-state resistance as a function of junction temperature; typical values

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

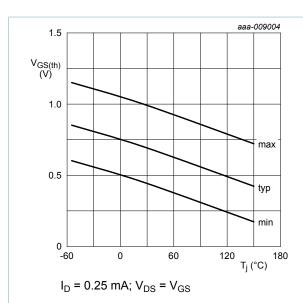


Fig. 14. TR1: gate-source threshold voltage as a function of junction temperature

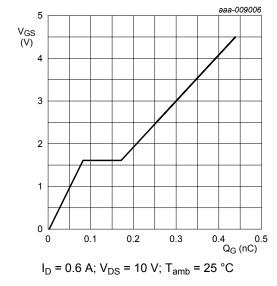


Fig. 16. TR1: gate-source voltage as a function of gate charge; typical values

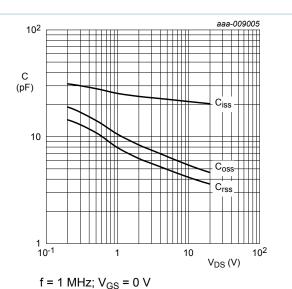


Fig. 15. TR1: input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

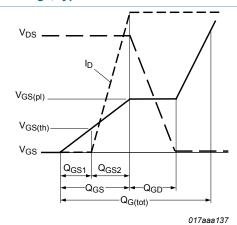


Fig. 17. Gate charge waveform definitions

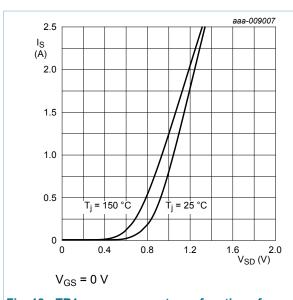


Fig. 18. TR1: source current as a function of sourcedrain voltage; typical values

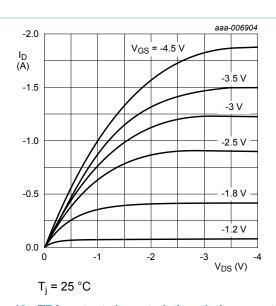


Fig. 19. TR2: output characteristics; drain current as a function of drain-source voltage; typical values

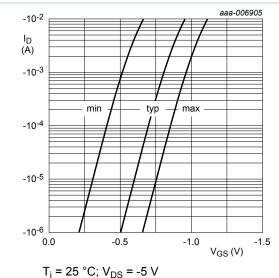


Fig. 20. TR2: sub-threshold drain current as a function of gate-source voltage

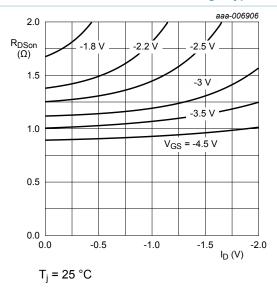


Fig. 21. TR2: drain-source on-state resistance as a function of drain current; typical values

20 V, complementary N/P-channel Trench MOSFET

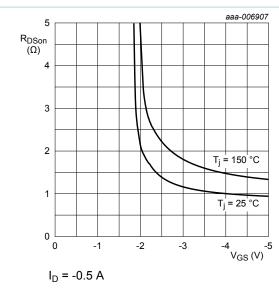


Fig. 22. TR2: drain-source on-state resistance as a function of gate-source voltage; typical values

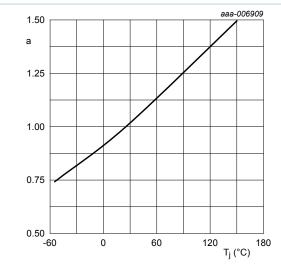


Fig. 24. TR2: normalized drain-source on-state resistance as a function of junction temperature; typical values

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

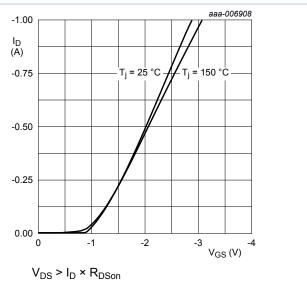
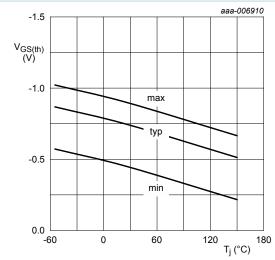


Fig. 23. TR2: transfer characteristics; drain current as a function of gate-source voltage; typical values

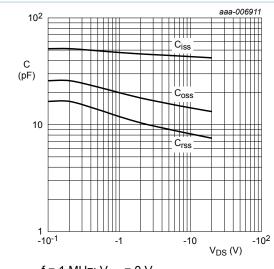


 I_D = -0.25 mA; V_{DS} = V_{GS}

Fig. 25. TR2: gate-source threshold voltage as a function of junction temperature

20 V, complementary N/P-channel Trench MOSFET

aaa-006912



 $f = 1 MHz; V_{GS} = 0 V$

Fig. 26. TR2: input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

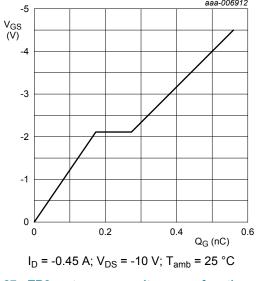


Fig. 27. TR2: gate-source voltage as a function of gate charge; typical values

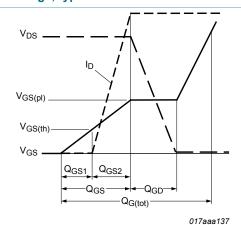


Fig. 28. Gate charge waveform definitions

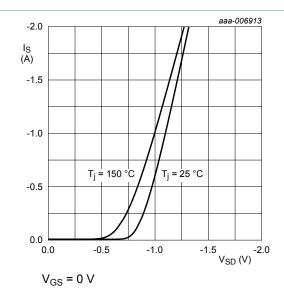
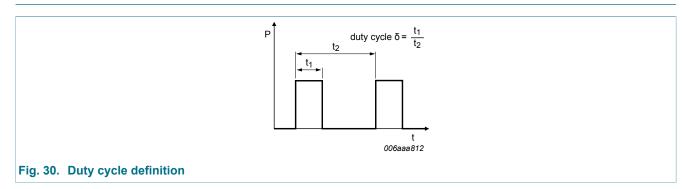


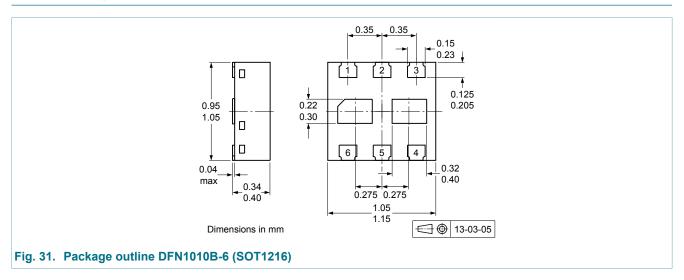
Fig. 29. TR2: source current as a function of sourcedrain voltage; typical values

20 V, complementary N/P-channel Trench MOSFET

11. Test information

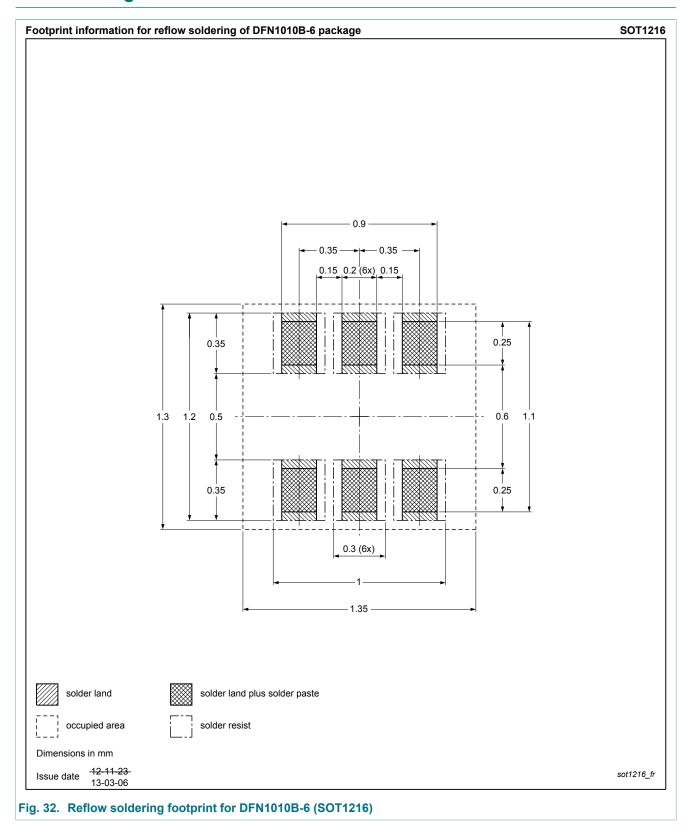


12. Package outline



15 / 20

13. Soldering



PMCXB900UE

All information provided in this document is subject to legal disclaimers.

© NXP N.V. 2013. All rights reserved

20 V, complementary N/P-channel Trench MOSFET

14. Revision history

Table 8. Revision history

Data sheet ID	Release date	Data sheet status	Change notice	Supersedes
PMCXB900UE v.1	20131007	Product data sheet	-	-

20 V, complementary N/P-channel Trench MOSFET

15. Legal information

15.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

15.2 Definitions

Preview — The document is a preview version only. The document is still subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

15.3 Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. NXP Semiconductors takes no responsibility for the content in this document if provided by an information source outside of NXP Semiconductors.

In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of NXP Semiconductors.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors and its suppliers accept no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

Terms and conditions of commercial sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the

PMCXB900UE

All information provided in this document is subject to legal disclaimers.

© NXP N.V. 2013. All rights reserved

20 V, complementary N/P-channel Trench MOSFET

grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific NXP Semiconductors product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. NXP Semiconductors accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without NXP Semiconductors' warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond NXP Semiconductors' specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies NXP Semiconductors for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond NXP Semiconductors' standard warranty and NXP Semiconductors' product specifications.

Translations — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

15.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

Adelante, Bitport, Bitsound, CoolFlux, CoReUse, DESFire, EZ-HV, FabKey, GreenChip, HiPerSmart, HITAG, I²C-bus logo, ICODE, I-CODE, ITEC, Labelution, MIFARE, MIFARE Plus, MIFARE Ultralight, MoReUse, QLPAK, Silicon Tuner, SiliconMAX, SmartXA, STARPlug, TOPFET, TrenchMOS, TriMedia and UCODE — are trademarks of NXP B.V.

 $\ensuremath{\mathbf{HD}}$ $\ensuremath{\mathbf{Radio}}$ and $\ensuremath{\mathbf{HD}}$ $\ensuremath{\mathbf{Radio}}$ logo — are trademarks of iBiquity Digital Corporation.

NXP Semiconductors

PMCXB900UE

20 V, complementary N/P-channel Trench MOSFET

16. Contents

1	General description	1
2	Features and benefits	1
3	Applications	1
4	Quick reference data	1
5	Pinning information	2
6	Ordering information	2
7	Marking	3
8	Limiting values	3
9	Thermal characteristics	6
10	Characteristics	7
11	Test information	15
12	Package outline	15
13	Soldering	16
14	Revision history	17
15	Legal information	18
15.1	Data sheet status	18
15.2	Definitions	18
15.3	Disclaimers	18
15.4	Trademarks	19

© NXP N.V. 2013. All rights reserved

For more information, please visit: http://www.nxp.com For sales office addresses, please send an email to: salesaddresses@nxp.com Date of release: 7 October 2013